Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/029,769	RILEY ET AL.		
Examiner	Art Unit		
Tan Dean D. Nguyen	3629		

	SEARCHED				
Class	Subclass	Date	Examiner		
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Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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